

Maximum Ratings – Q1 (@T_A = +25°C, unless otherwise specified.)

Characteristic	Symbol	Value	Unit
Drain-Source Voltage	V _{DSS}	25	V
Gate-Source Voltage	V _{GSS}	-0.5 +8	V
Continuous Drain Current (Note 5) V _{GS} = 4.5V	I _D	0.5	Α
Maximum Continuous Body Diode Forward Current (Note 6)	Is	1.2	Α
Pulsed Drain Current (Note 6)	I _{DM}	1.5	Α

Maximum Ratings – Q2 (@T_A = +25°C, unless otherwise specified.)

Characteristic		Symbol	Value	Unit
Drain-Source Voltage		V_{DSS}	-12	V
Gate-Source Voltage		V_{GSS}	±8	V
Continuous Drain Current (Note 5) V _{GS} = -4.5V	Steady State		-3.9	Α
Continuous Diain Current (Note 5) VGS = -4.5V	Note 9	I_{D}	-17.4	Α
Continuous Drain Current (Note 5) V _{GS} = -2.5V		-2.82	Α	
Maximum Continuous Body Diode Forward Current (Note 6)	I _S	-40	Α	
Pulsed Drain Current (Note 6)		I _{DM}	-40	A

Thermal Characteristics

Characteristic		Symbol	Value	Unit
Power Dissipation (Note 5)		P_{D}	1.3	W
Thermal Resistance, Junction to Ambient (Note 5)	Steady State	D	100	°C/W
Thermal Resistance, Junction to Ambient (Note 5)	Note 9	$R_{\theta JA}$	5	
Thermal Resistance, Junction to Case (Note 5)		$R_{\theta JC}$	36	°C/W
Operating and Storage Temperature Range		T_J, T_{STG}	-55 to +150	°C

Electrical Characteristics - Q1 (@T_A = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 7)						
Drain-Source Breakdown Voltage	BV _{DSS}	25	_	_	V	$V_{GS} = 0V, I_D = 250\mu A$
Zero Gate Voltage Drain Current	I _{DSS}	_	_	1	μΑ	$V_{DS} = 20V, V_{GS} = 0V$
Gate-Source Leakage	I _{GSS}	_	_	100	nA	$V_{GS} = 8V$, $V_{DS} = 0V$
ON CHARACTERISTICS (Note 7)						
Gate Threshold Voltage	V _{GS(TH)}	0.65	0.85	1.5	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
Static Drain-Source On-Resistance	R _{DS(ON)}	_	3.8	4	Ω	$V_{GS} = 4.5V, I_D = 0.4A$
Diode Forward Voltage	V_{SD}	_	0.76	1.2	V	$V_{GS} = 0V, I_{S} = 0.29A$
DYNAMIC CHARACTERISTICS (Note 8)						•
Input Capacitance	Ciss		27.6	_		V _{DS} = 10V, V _{GS} = 0V, f = 1.0MHz
Output Capacitance	Coss	_	8.5	_	pF	
Reverse Transfer Capacitance	C _{rss}	_	3.3	_		
Gate Resistance	Rg		25	_	Ω	$V_{DS} = 0V$, $V_{GS} = 0V$, $f = 1MHz$
Total Gate Charge (V _{GS} = 4.5V)	Qq	_	0.4	_		
Total Gate Charge (V _{GS} = 10V)	Q_g	_	0.9	_	nC	$V_{DS} = 5V, I_{D} = 0.2A$
Gate-Source Charge	Q _{gs}	_	0.1	_	iiC	
Gate-Drain Charge	Q _{gd}	_	0.04	_		
Turn-On Delay Time	t _{D(ON)}	_	2.5	_		V _{GS} = 4.5V, V _{DS} = 6V,
Turn-On Rise Time	t _R	_	1.4	_		
Turn-Off Delay Time	t _{D(OFF)}	_	5.7	_	ns	$R_G = 50\Omega, I_D = 0.5A$
Turn-Off Fall Time	t _F	_	4.3	_		

Notes:

- 5. Device mounted on FR-4 substrate PC board, 2oz copper, with 1in. square copper plate.
 6. Repetitive rating, pulse width limited by junction temperature.
 7. Short duration pulse test used to minimize self-heating effect.
 8. Guaranteed by design. Not subject to production testing.
 9. Pulse Test: Pulse Width < 300µs, Duty Cycle < 2.0%.



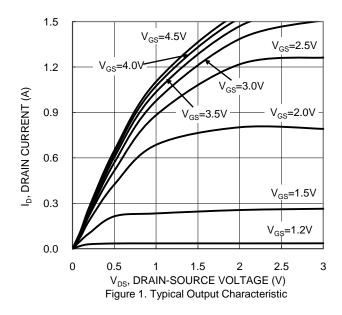
Electrical Characteristics – Q2 (@T_A = +25°C, unless otherwise specified.)

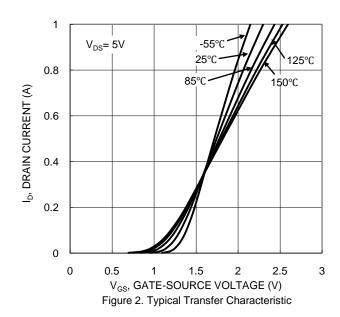
Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 10)						
Drain-Source Breakdown Voltage	BV _{DSS}	-12	_	_	V	$V_{GS} = 0V, I_D = -250\mu A$
Zero Gate Voltage Drain Current	I _{DSS}	1	_	-1	μΑ	$V_{DS} = -6.4V, V_{GS} = 0V$
Gate-Source Leakage	I _{GSS}	_	_	±10	μΑ	$V_{GS} = \pm 8V$, $V_{DS} = 0V$
ON CHARACTERISTICS (Note 10)						
Gate Threshold Voltage	$V_{GS(TH)}$	-0.35	_	-1.5	V	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$
		I	_	55		$V_{GS} = -4.5V$, $I_D = -2.8A$
Static Drain-Source On-Resistance	R _{DS(ON)}	l	_	70	mΩ	$V_{GS} = -2.5V$, $I_D = -2.5A$
	, ,	_		100		$V_{GS} = -1.8V, I_{D} = -2.0A$
Diode Forward Voltage	V_{SD}	_	_	-1.2	V	$V_{GS} = 0V, I_{S} = -0.6A$
DYNAMIC CHARACTERISTICS (Note 11)						
Input Capacitance	C _{iss}	l	9.7	_		V _{DS} = -6V, V _{GS} = 0V, f = 1MHz
Output Capacitance	C _{oss}	_	393	_	pF	
Reverse Transfer Capacitance	C _{rss}	_	1.9	_		
Gate Resistance	Rg	_	1846	_	Ω	$V_{DS} = 0V$, $V_{GS} = 0V$, $f = 1MHz$
Total Gate Charge (V _{GS} = -4.5V)	Qg	_	24.5	_		
Gate-Source Charge	Qgs	_	3.3	_	nC	$V_{DS} = -6V, I_{D} = -2.8A$
Gate-Drain Charge	Q _{gd}	_	7.3	_		
Turn-On Delay Time	t _{D(ON)}	_	1.2	_		V _{GS} = -4.5V, V _{DS} = -6V,
Turn-On Rise Time	t _R	_	2.7	_	1	
Turn-Off Delay Time	t _{D(OFF)}	_	9.8	_	μs	$R_G = 6\Omega$, $I_D = -2.8A$
Turn-Off Fall Time	t _F	_	6.5	_	1	

Notes:

- 10. Short duration pulse test used to minimize self-heating effect.
- 11. Guaranteed by design. Not subject to production testing.

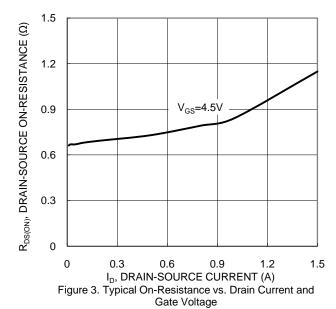
Typical Characteristics - N-CHANNEL

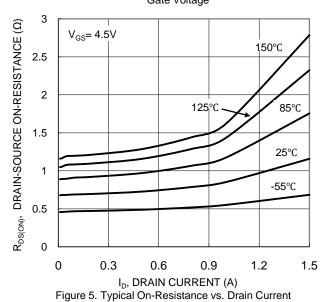


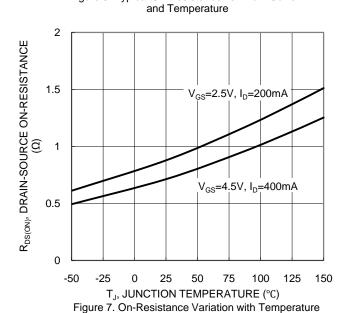


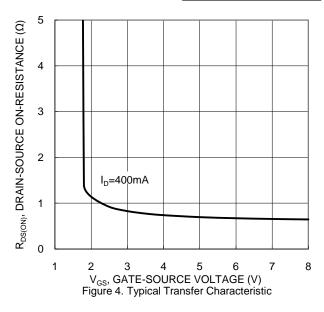


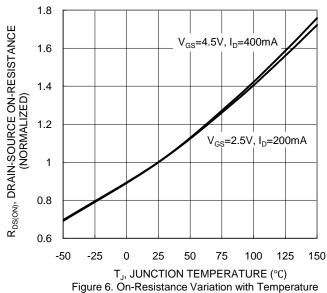








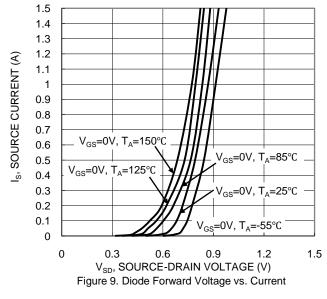


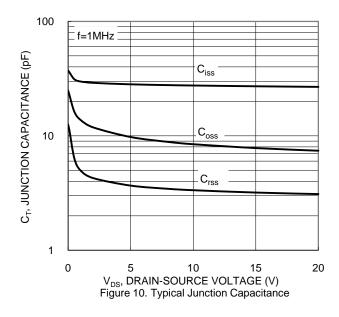


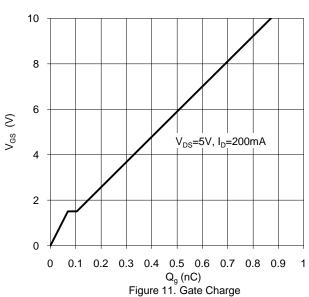
1.2 $V_{GS(TH)},$ GATE THRESHOLD VOLTAGE (V) 1.1 1 I_D=1mA 0.9 8.0 $I_D=250\mu A$ 0.7 0.6 0.5 0.4 -25 125 150 -50 0 25 50 75 100 T_J, JUNCTION TEMPERATURE (°C) Figure 8. Gate Threshold Variation vs. Junction

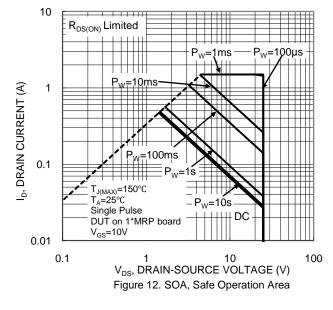
Temperature

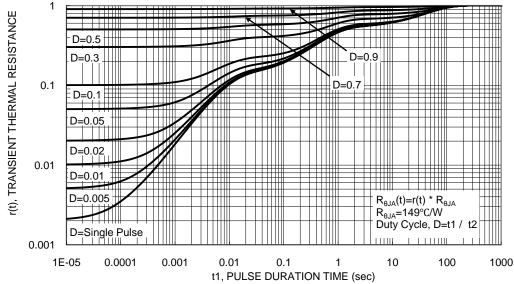






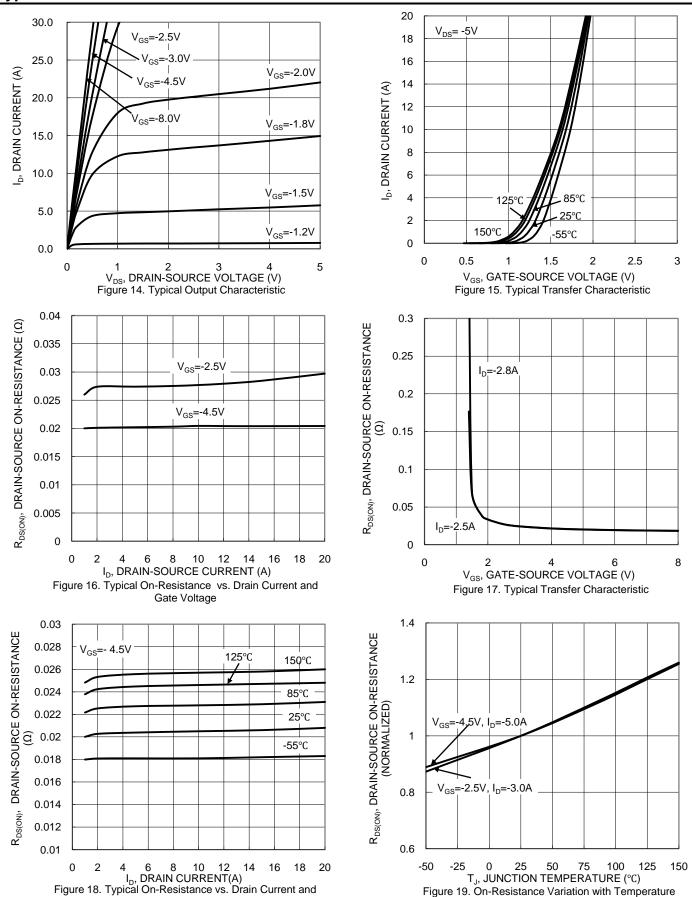








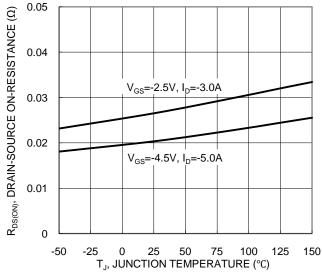
Typical Characteristics - P-CHANNEL

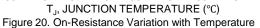


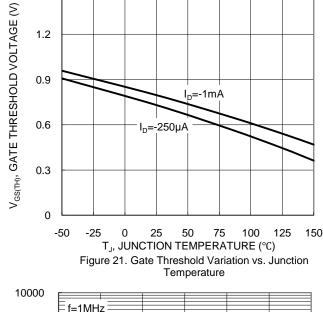
Temperature



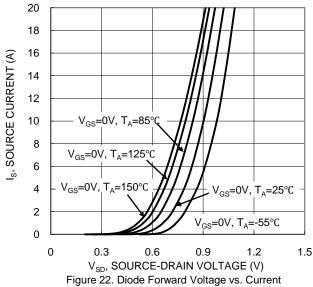








1.5



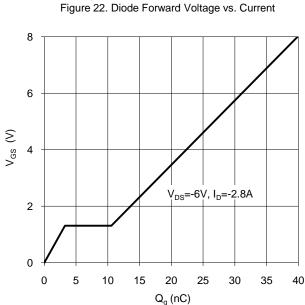
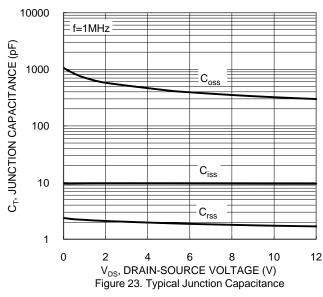
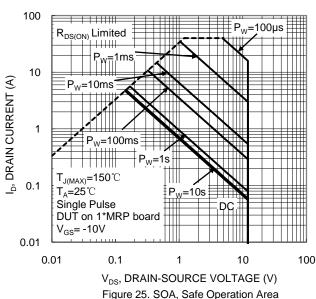


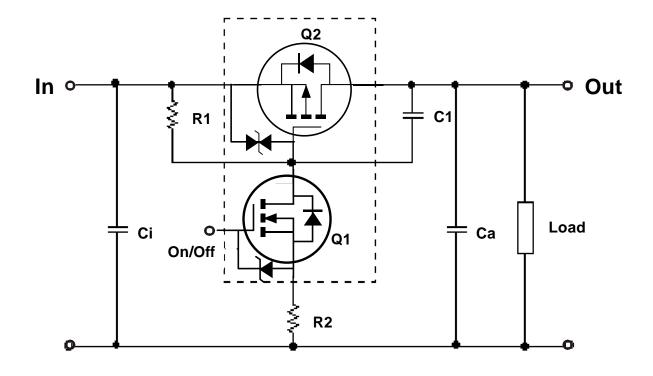
Figure 24. Gate Charge





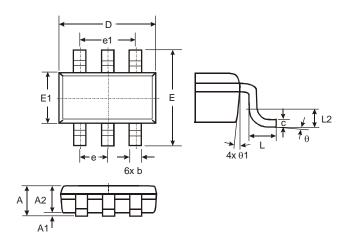


Application Circuit



Package Outline Dimensions

Please see AP02002 at http://www.diodes.com/datasheets/ap02002.pdf for the latest version.

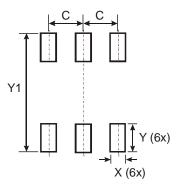


TSOT26					
Dim	Min	Max	Тур		
Α	-	1.00	1		
A1	0.01	0.10	1		
A2	0.84	0.90	-		
D	_	_	2.90		
Е	_	-	2.80		
E1	_	_	1.60		
b	0.30	0.45	_		
C	0.12	0.20	1		
е	_	_	0.95		
e1	_	_	1.90		
L	0.30	0.50			
L2	_	_	0.25		
θ	0°	8°	4°		
θ1	4°	12°	_		
All Dimensions in mm					



Suggested Pad Layout

Please see AP02001 at http://www.diodes.com/datasheets/ap02001.pdf for the latest version.



Dimensions	Value (in mm)
С	0.950
Х	0.700
Υ	1.000
Y1	3.199

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